



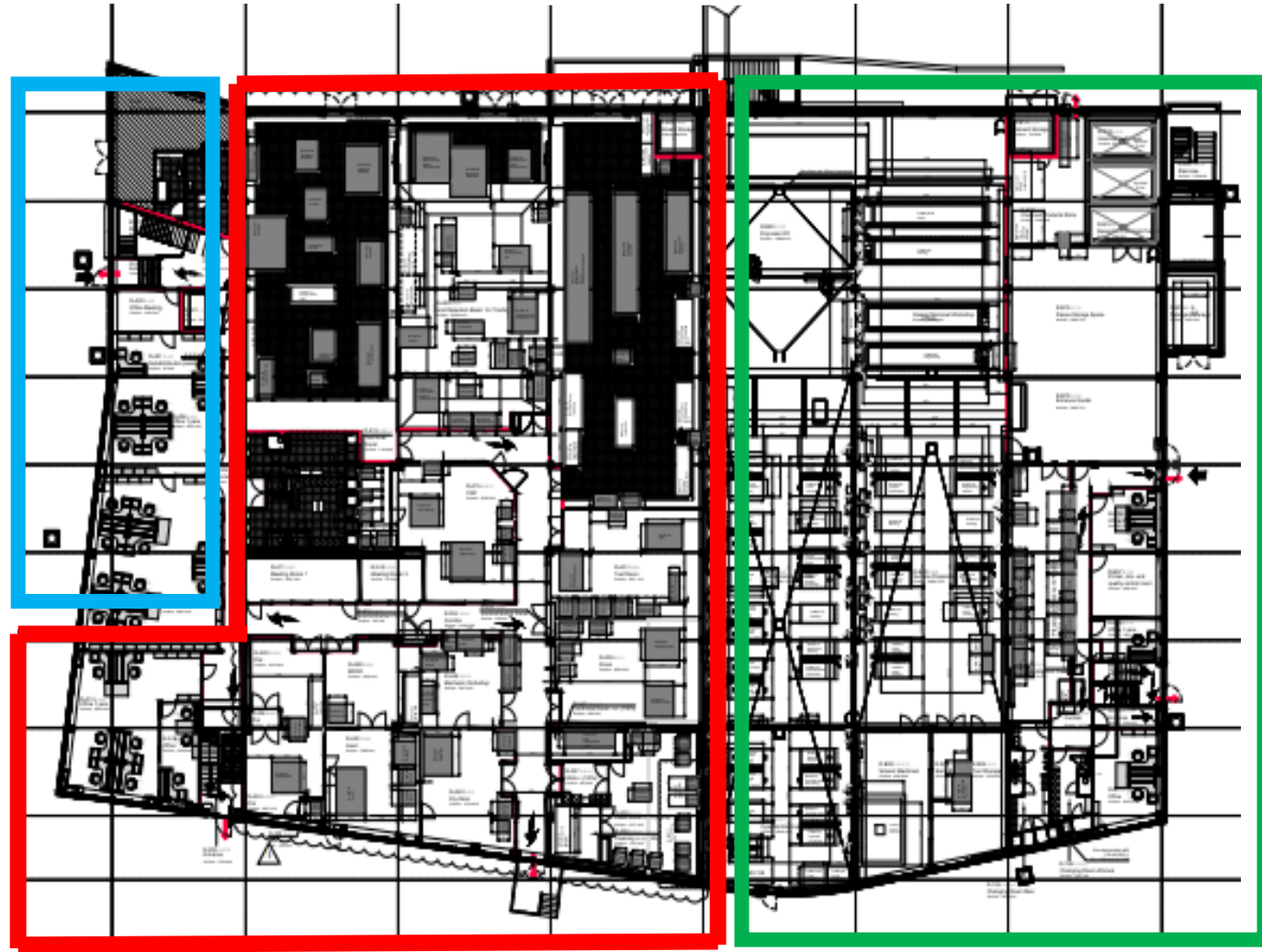
Rui De Oliveira December/11/2022



- 20 persons
- 13 persons from a contracting company → only productions using well established technologies.
- 7 CERN staff → 3 administration and 4 dedicated to R&D prototypes.
- 1400 square meters (new building finished in 2018).
- Making PCBs since 1965
- Mandate:
 - Produce parts difficult to find in industry.
 - Provide to CERN users expertise in interconnections technologies.
 - Make sometime mass production.

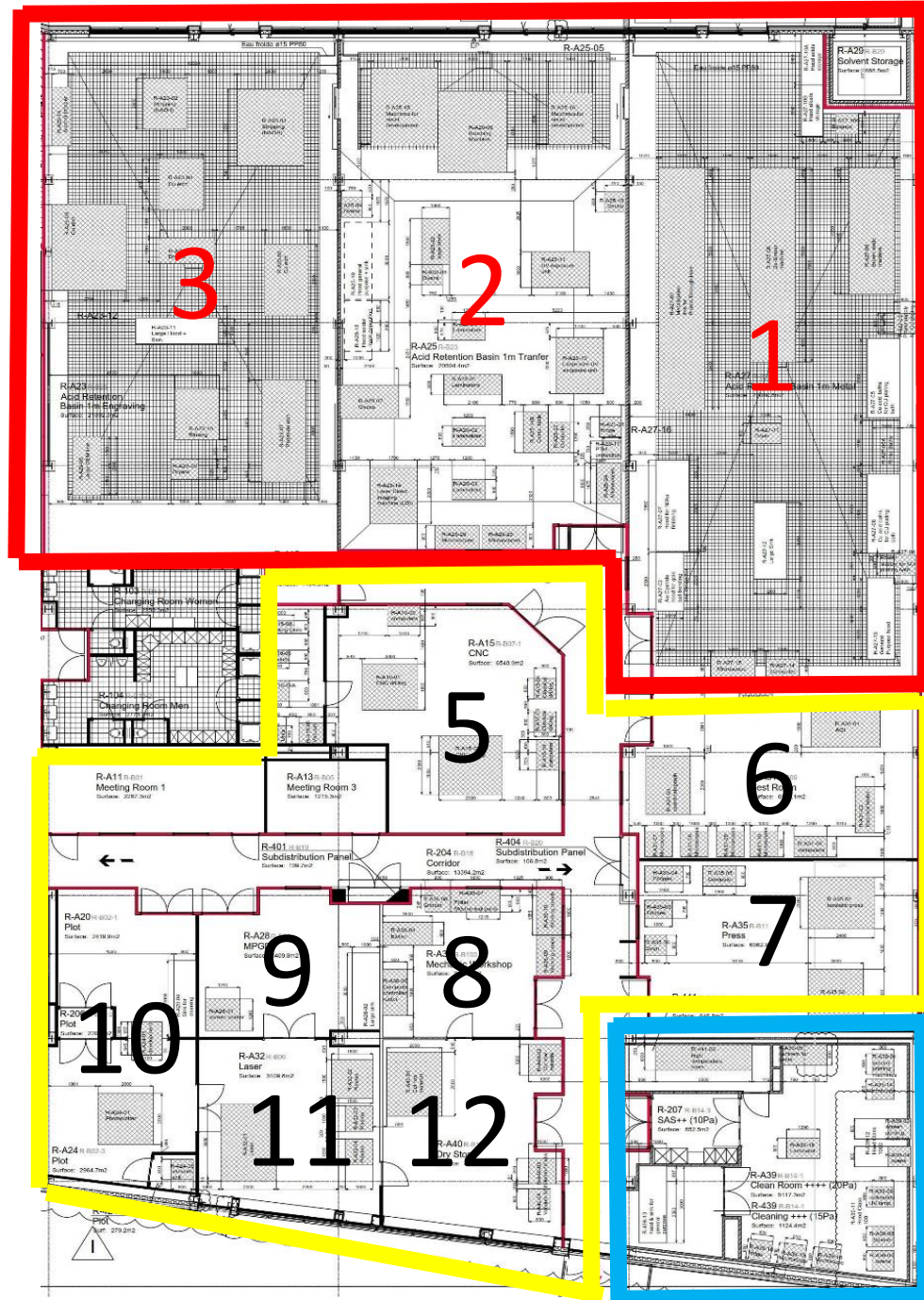
PCB Assembly Lab
PCB design office

Building 107



MPT workshop (EP Dept. -20persons)

Surface treatment workshop



Wet processing Area
 1/Plating facility
 2/Photo processes
 3/Chemical Etching

Dry processing Area
 5/Drilling/milling
 6/Test
 7/Pressing
 8/MPGD
 9/Chemical analysis
 10/Photo mask lab
 11/Vacuum deposition
 12/Dry store

Clean room



Plating facility

- Cu : bath
- Ni : bath
- Au Bath
- Carbon Horizontal
- desmear Horizontal
- Cu oxide Horizontal

Wet area



Chemical etching facility

- Cu,SS,Al,Ni Horizontal
- Ti ,W, in hood
- Stripping horizontal line
- Cu/Ni horizontal plating line



Photo processes

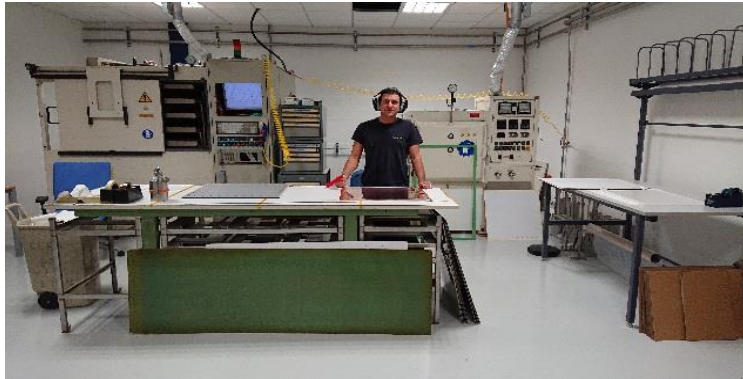
- UV exposure : std and large size
- Laser Direct imaging
- Lamination : std and large
- Soldermask spray deposition
- Horizontal development:
 - Solid resists
 - Coverlays
 - Solder masks
 - Liquid resists



CNC processes

- Drilling
- Milling

Dry area



Press facility

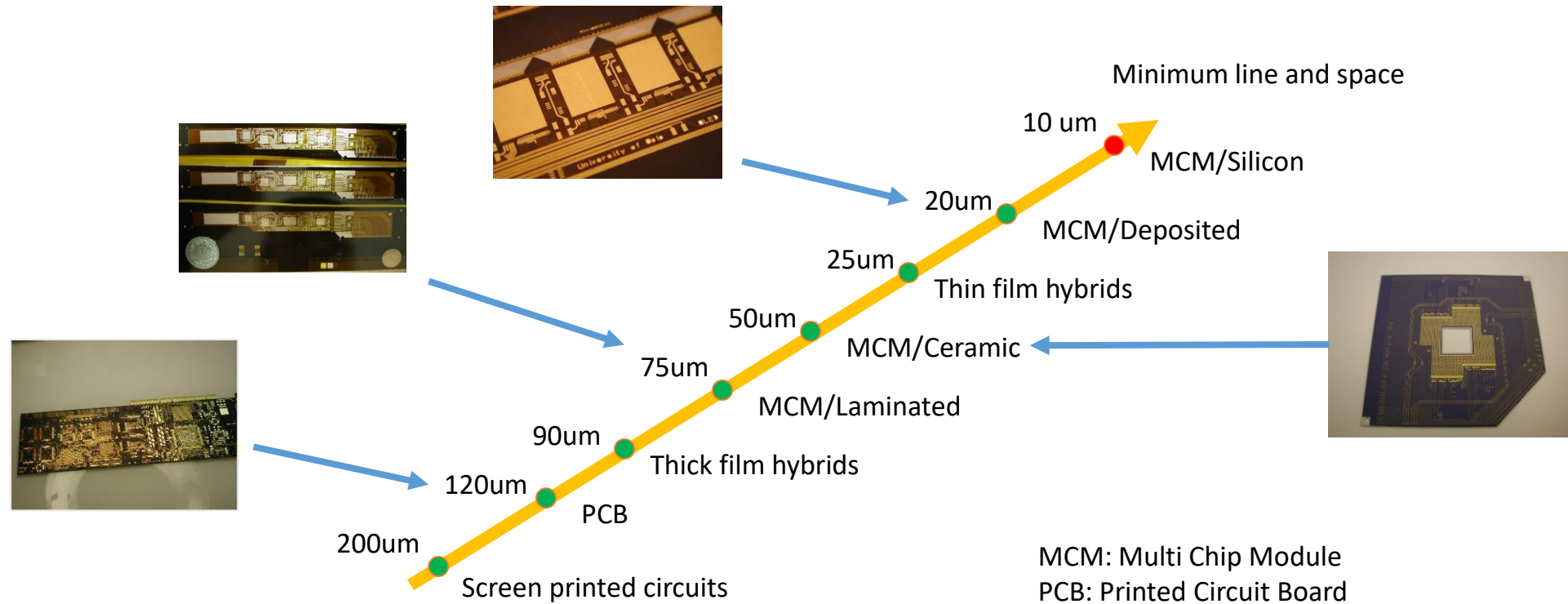
- Multilayer gluing
- 2 isostatic presses



Test facility

- Automatic Optical Inspection
- Electrical , flying probe tester
- microscopes

Core interconnections technologies available at MPT

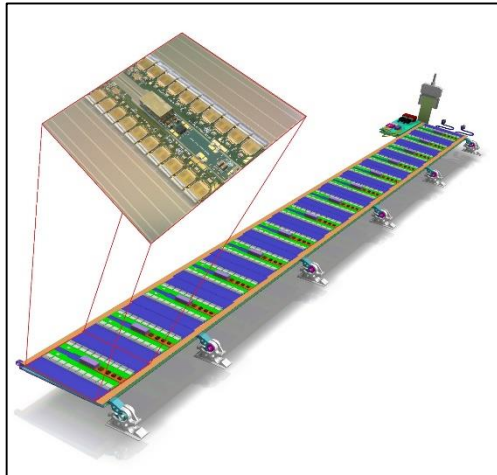


MPT activities



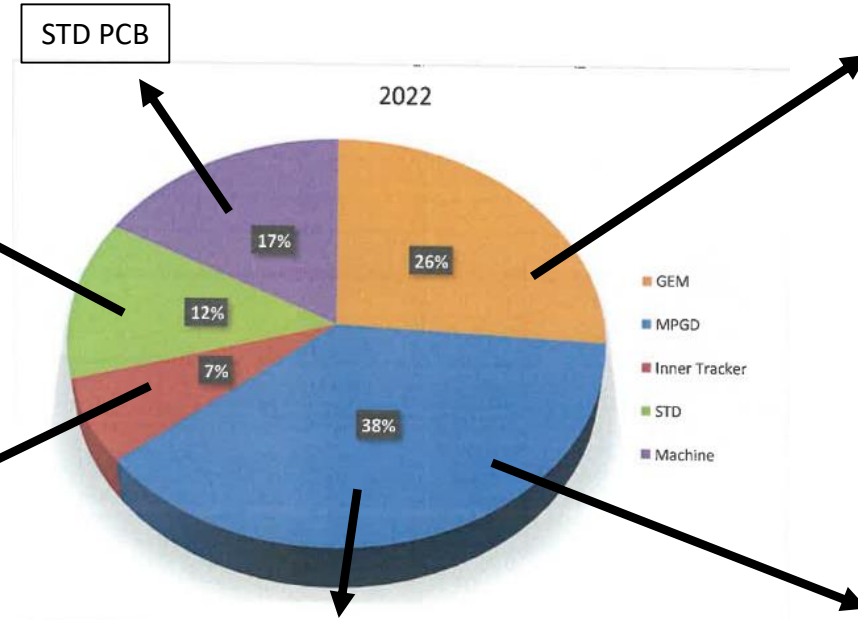
Component for LHC machine

- Ex: Quench heater flexes
- Different flavors , up to 14m long
 - More than 40 planned for 2023



Inner trackers components

- Ex: ATLAS ITK inner tracker long buses
- 1.4m x 15cm
 - 900 pieces to be produced in 2023/24



GEM

- Ex: CMS GE2.1
- Around 1000 GEM in total
 - 350 still to be produced in 2023
 - 4 technicians dedicated to GEM productions



Other detectors types

- Ex: T2K upgrade
- Resistive Micromegas detectors
 - 40 pieces requested ,
 - 20 pieces still to be produced in 2023

Heavy R&D program

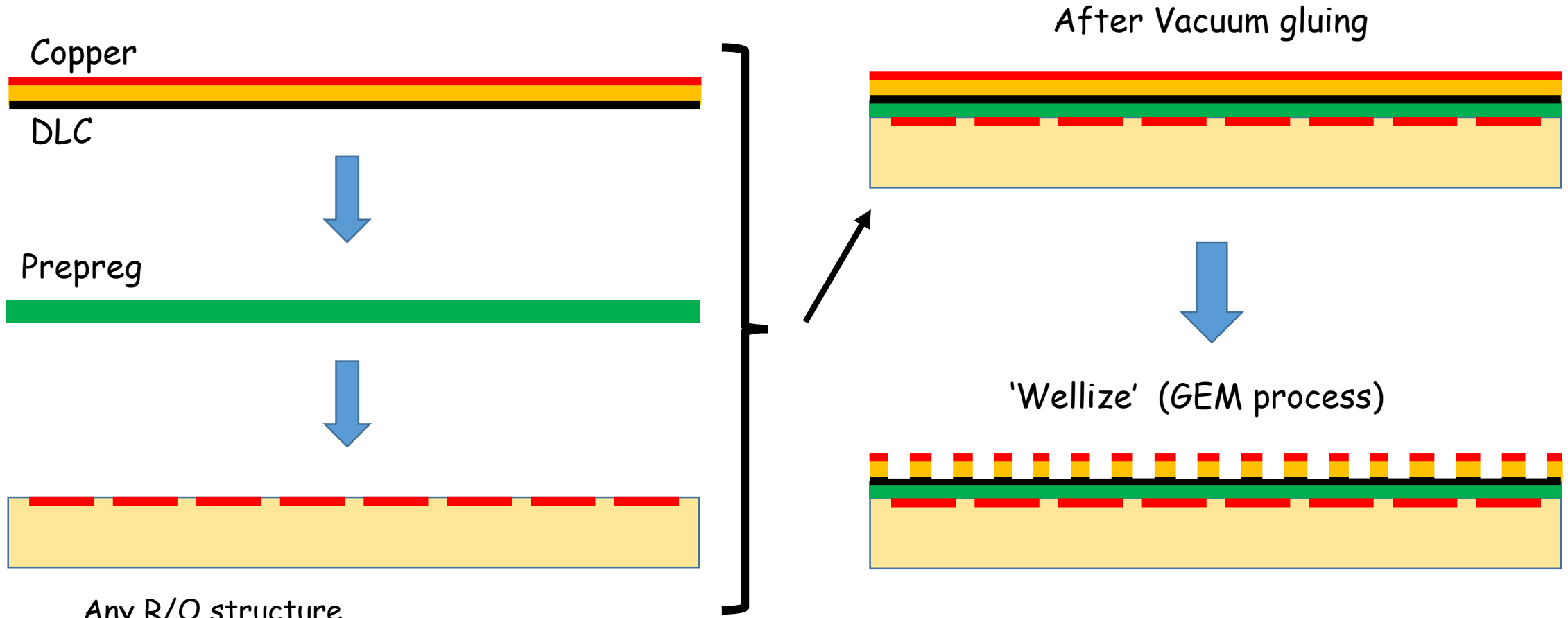
- PEP uRwell large size detectors
- Capacitive sharing detectors
- High rate detectors (MM & uRwell)
- Resistive GEMs
- Low IBF detectors
- High dynamic range detectors
- Fast timing detectors
- Low mass

We are working on many projects, but I want to highlight today 2 of them:

1/News on uRwell detectors production

2/New vacuum depositing machine

uRwell structure (reminder)



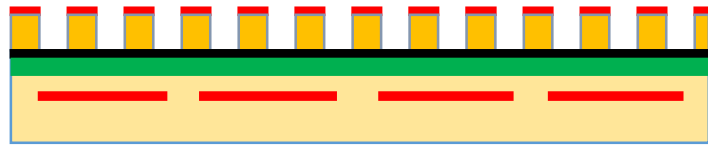
Any R/O structure

- X/Y , UVW , Pads, Capacitive sharing
- Rigid , flex, ultra thin flex
- Copper, Chromium, Aluminum etc..

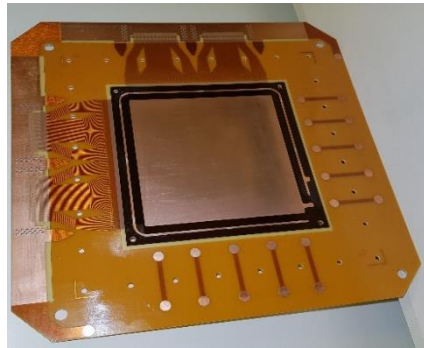
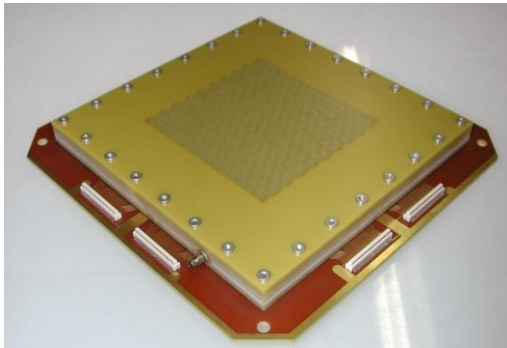
Many different ways to improve the rate capability

STD μ Rwell

DLC connected outside the active area



- Medium rate capability



10cm x 10cm
 μ Rwell detector
"study kit"

High rate μ Rwell

DLC connected in the active area

SG



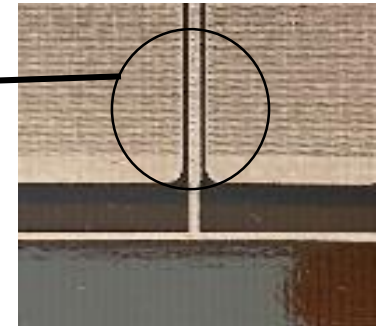
- DLC connected with Cu strips on the DLC



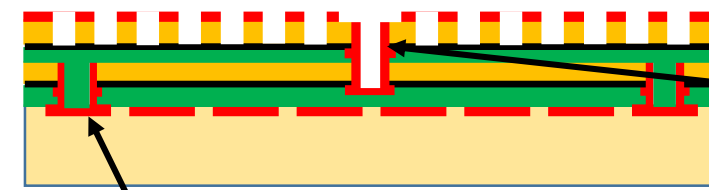
PEP



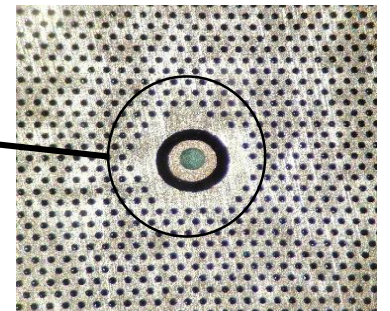
- DLC connected by plated strips



SBU



- 2 DLC layers connected by plated vias



PEP uRwell is for the time being our target

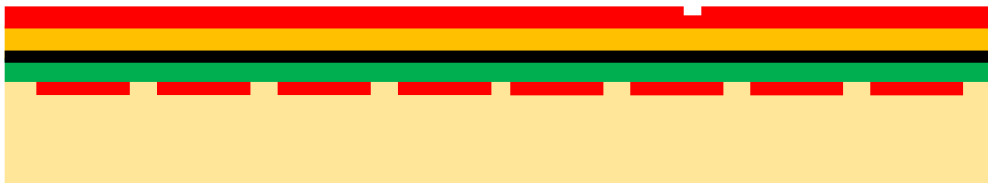
Pin hole



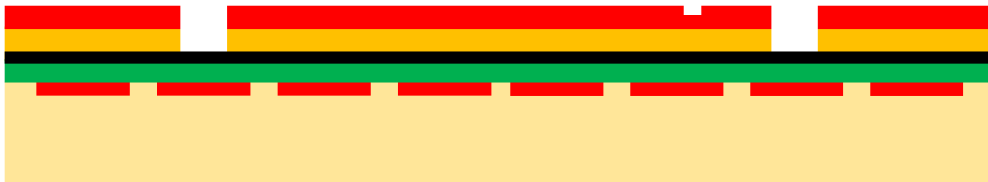
Around 95% yield

Basic structure

P → copper **P**lating
To hide the pin holes



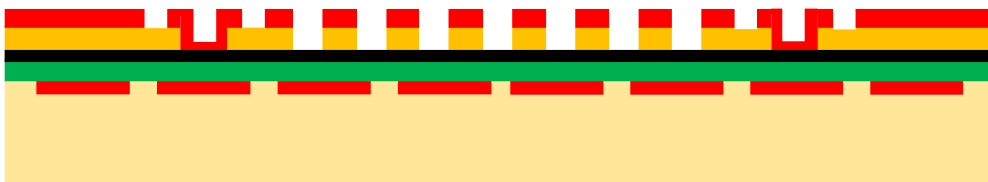
E → **E**tch copper and APICAL
No need for precise alignment



P → **P**late the holes or grooves
For DLC charge evacuation

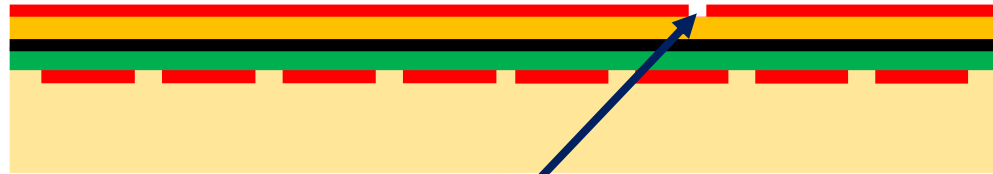


Wellization , easy alignment on visible patterns



PEP uRwell without pin hole protection

Around 60% yield



Basic structure

Pin hole



E → Etch copper and APICAL



P → Plate the holes or grooves

HV Direct HV to GND connection GND

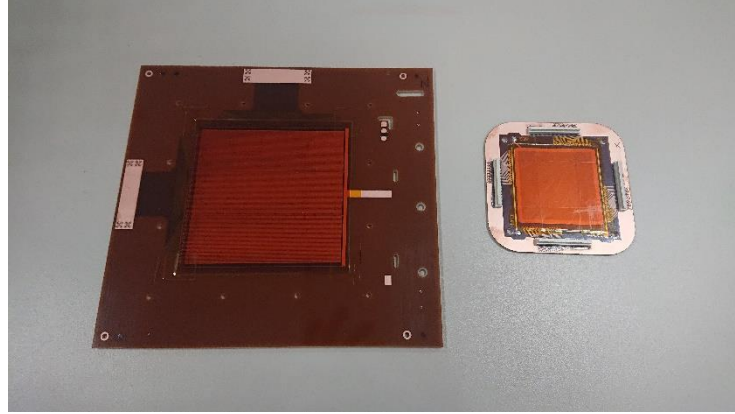


Wellization

E-cleaning



Oven et at 100 deg



Detector with Kapton protection
HV connections



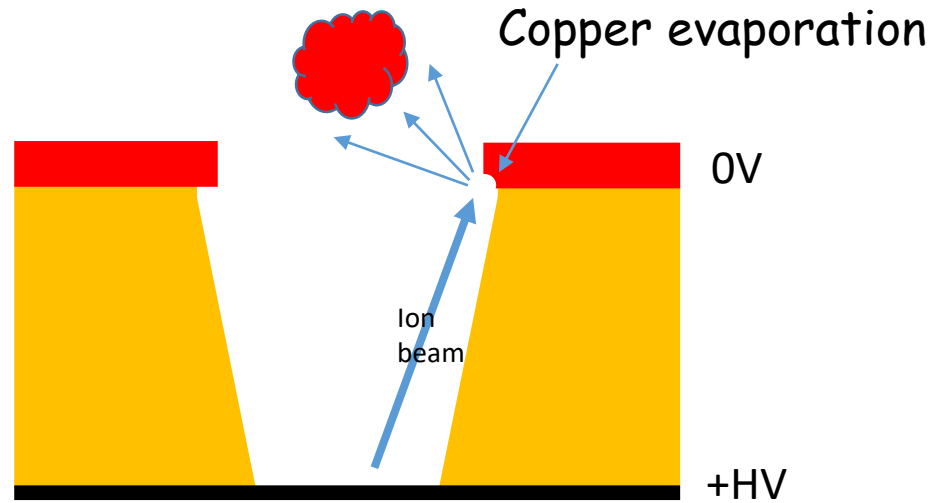
HV Power supply
10 to 20uA limitation

- 1/Minimum requirement → the detector should hold 250V in open air, leakage current $< 5\text{nA}$.
- 2/We put a kapton protection on the detector.
- 3/We then put the detector in oven @100 deg for 8 hours.
- 4/We apply 250V , 10 to 20uA limitation
- 5/We wait to reach a leakage current < 1 to 2nA and stay 2 hours with this current.
- 6/We then raise the voltage by 50V steps below 550V and then 20V steps.
- 7/We repeat step 3 and 4 till we reach 640V.

Depending on the detector size and the type of defect the E-cleaning can take a full week

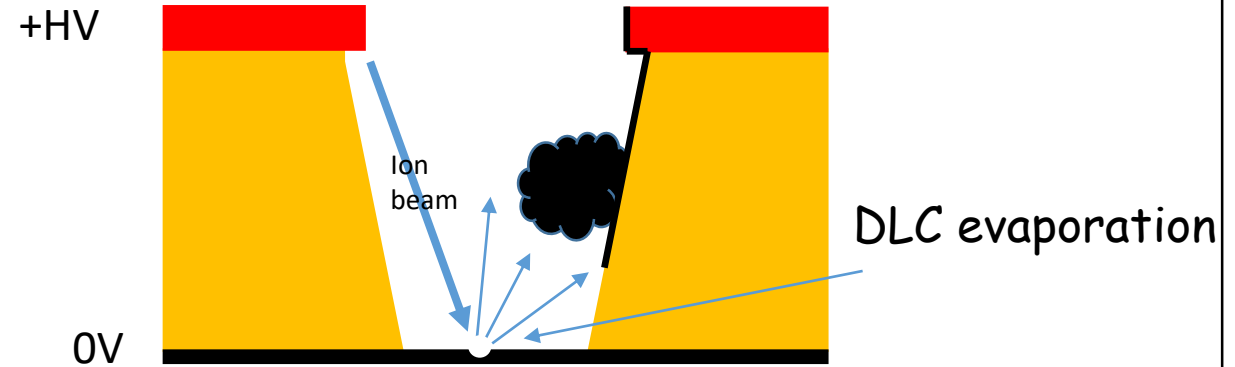
Explanation tentative presented at RD51 February/09/2022

Correct polarization → improvement



Evaporated Cu + Pi compounds are pulled out from the hole

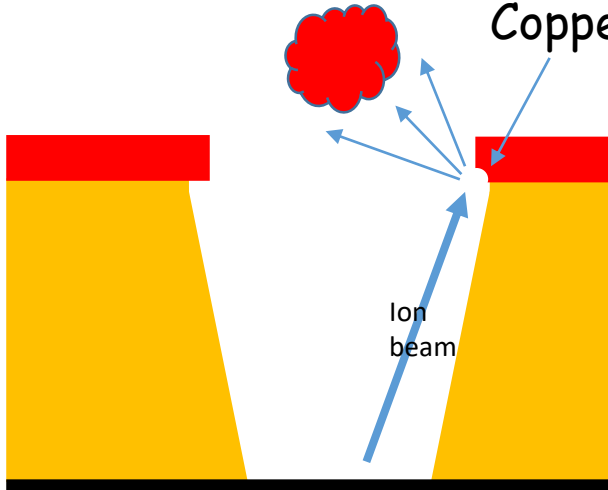
Wrong polarization → degradation



Evaporated DLC + PI compounds can condense on the walls

Explanation tentative presented at RD51 February/09/2022

Correct polarization → improvement



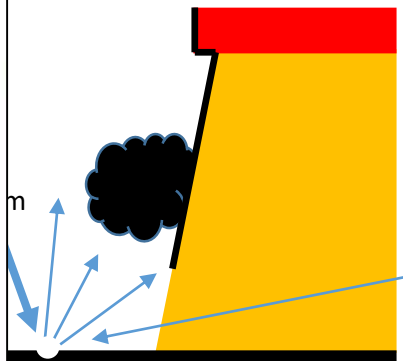
Copper evaporation

Ion beam

Evaporated Cu + Pi compound are pulled out from the hole

Detailed description: A schematic diagram showing a yellow trapezoidal structure with a red top layer. An ion beam (blue arrow) points towards the top surface. A red cloud representing evaporated copper is shown being pulled away from the top surface.

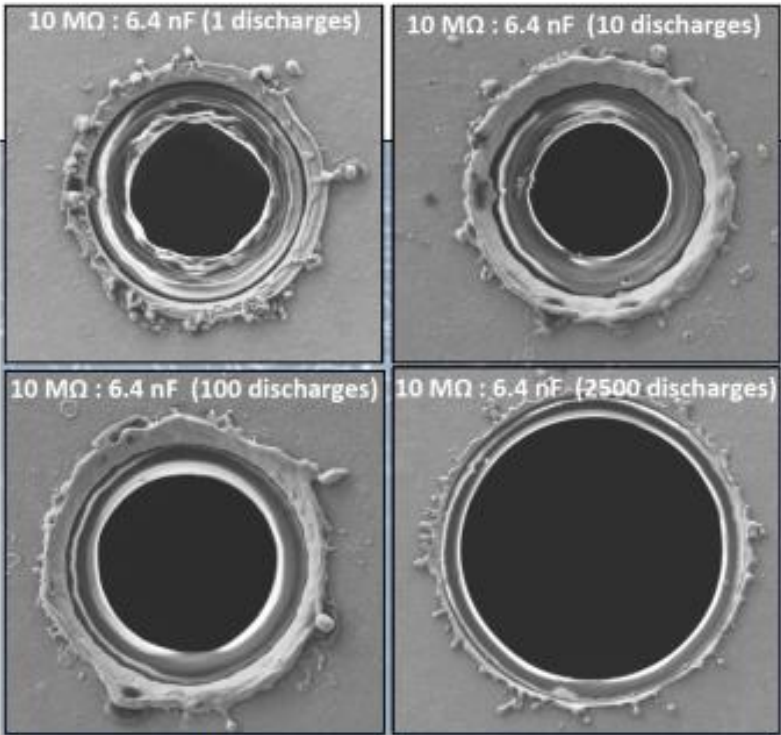
Wrong polarization → degradation



DLC evaporation

DLC + PI compoundsense on the walls

Detailed description: A schematic diagram showing a yellow trapezoidal structure with a red top layer. A black cloud representing evaporated DLC is shown being pulled away from the side wall of the structure.



10 MΩ : 6.4 nF (1 discharges)

10 MΩ : 6.4 nF (10 discharges)

10 MΩ : 6.4 nF (100 discharges)

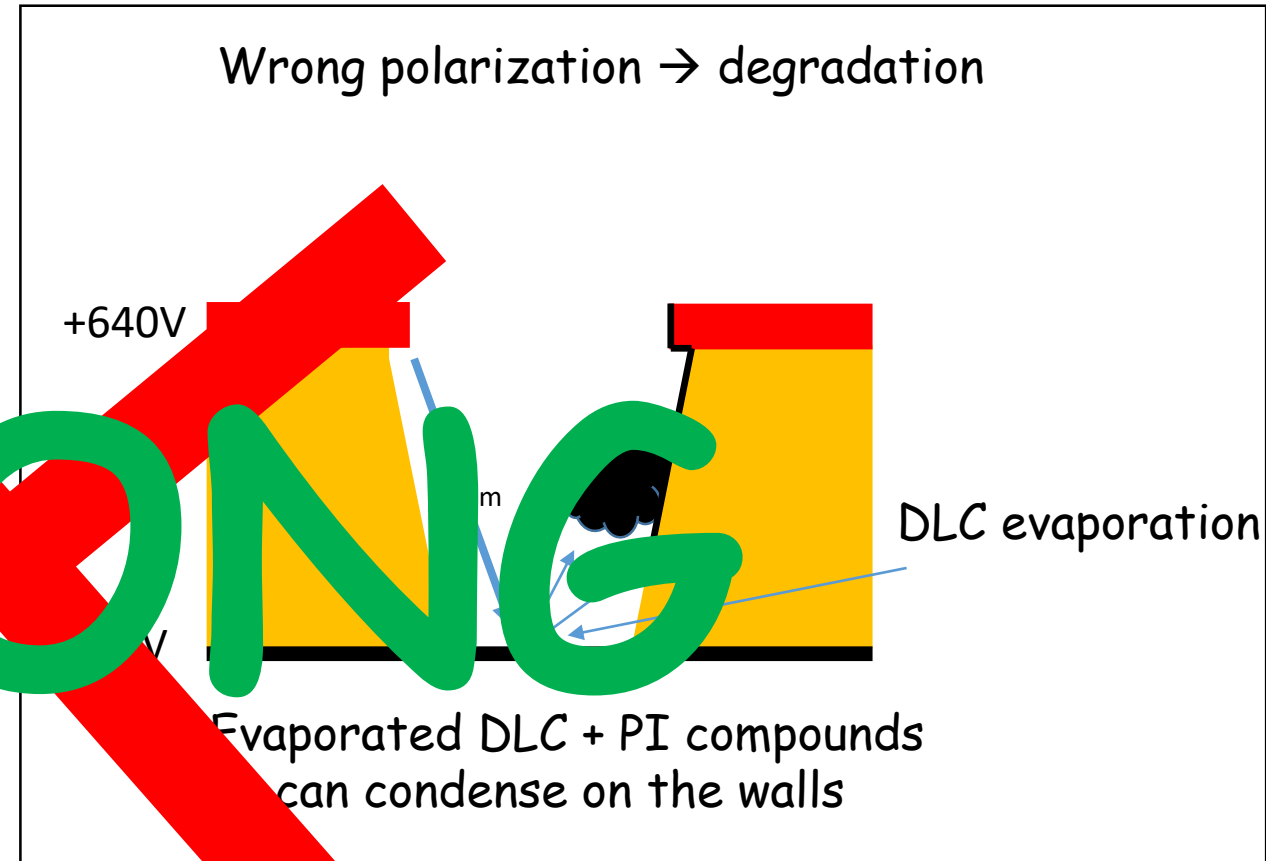
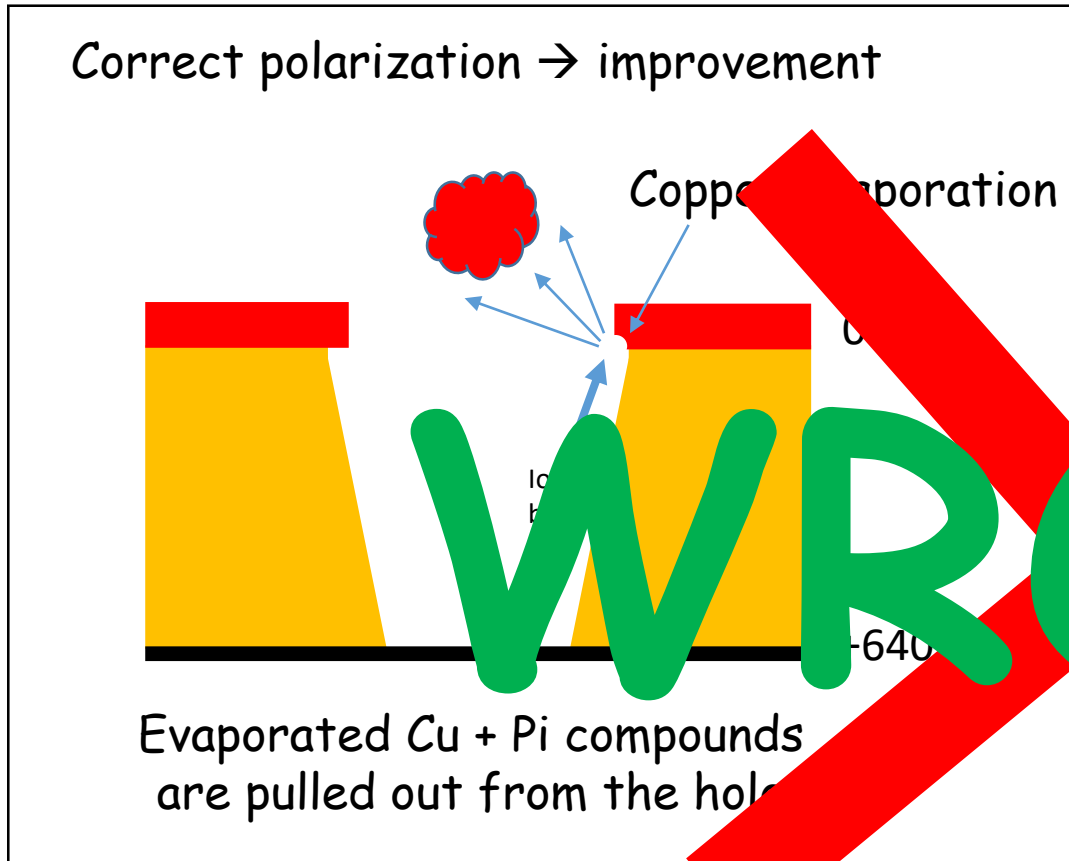
10 MΩ : 6.4 nF (2500 discharges)

Detailed description: A 2x2 grid of SEM images showing the cross-section of a hole in a GEM. The top-left image (1 discharge) shows a clean hole. The top-right image (10 discharges) shows some material pulled out. The bottom-left image (100 discharges) shows significant material pulled out. The bottom-right image (2500 discharges) shows a severely eroded hole.

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<https://indico.cern.ch/event/709670/contributions/3008626/>

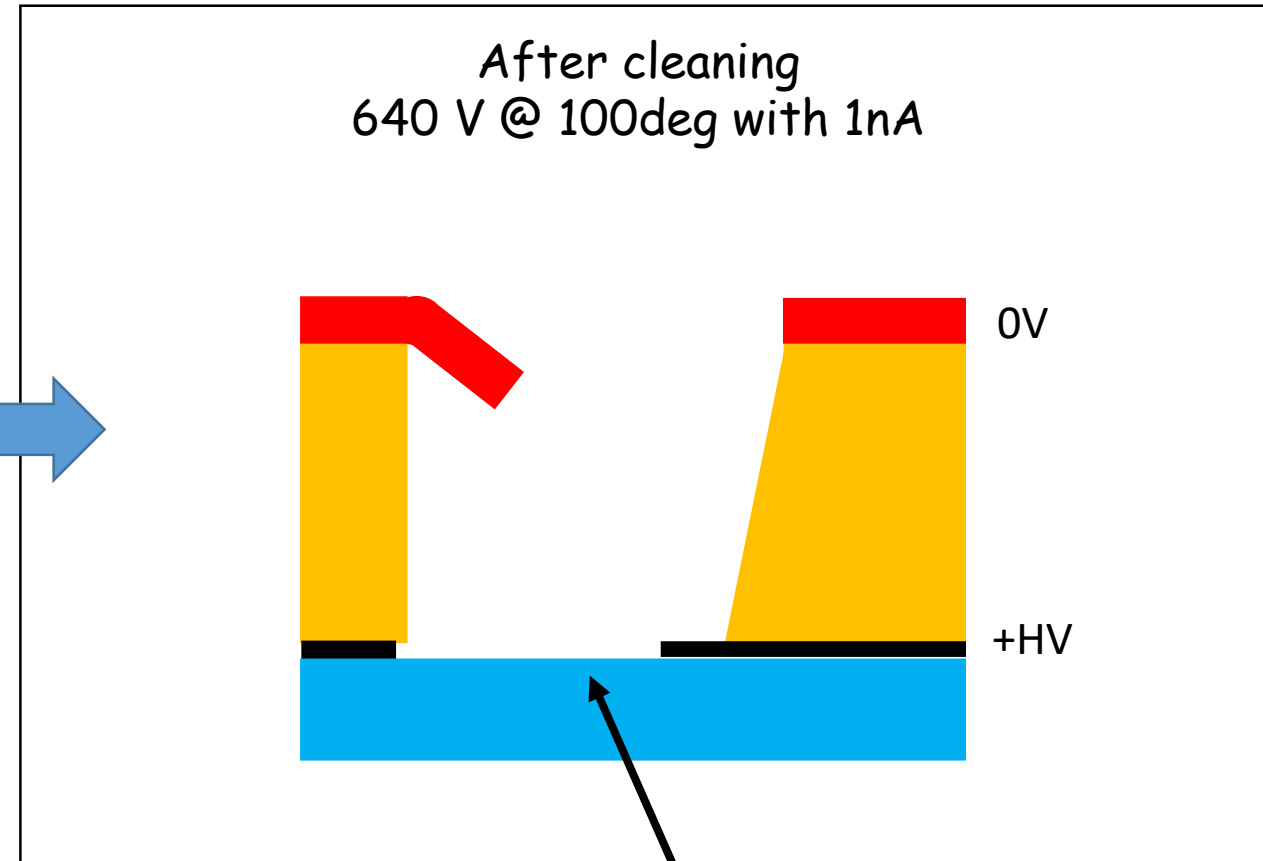
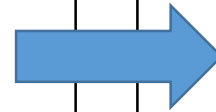
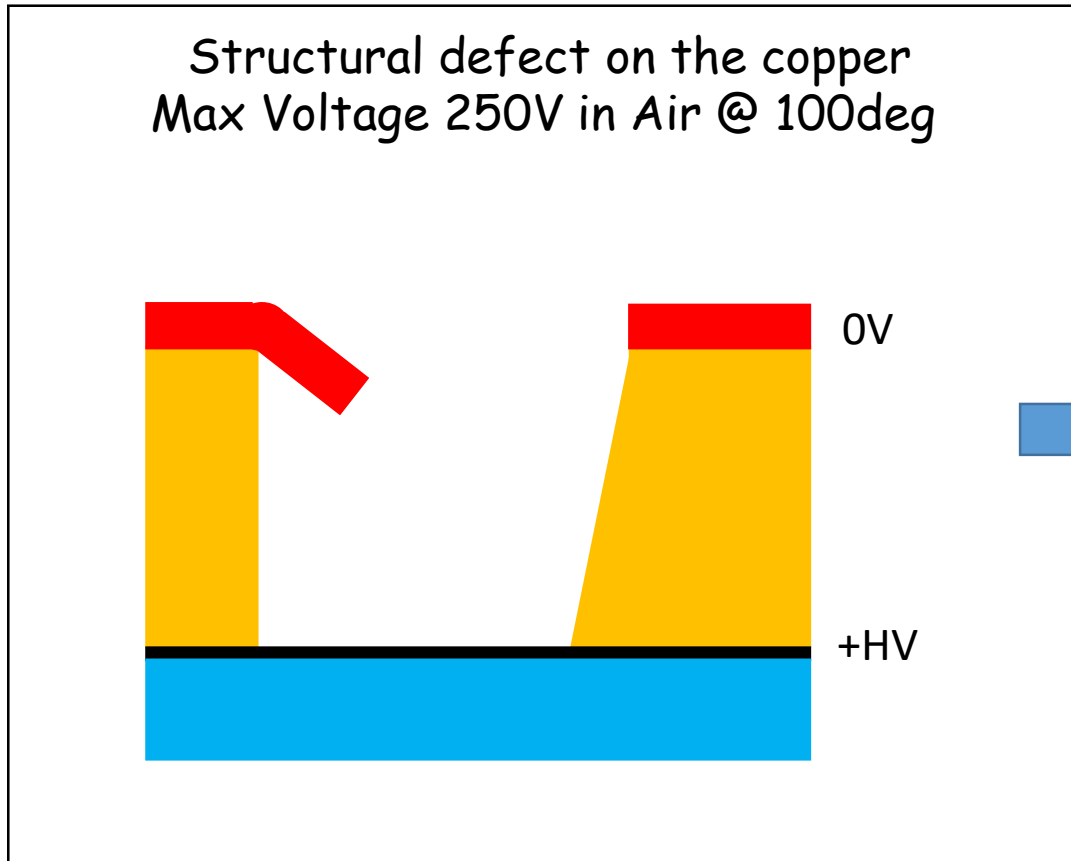
In the GEM case we can clearly see material pulled out from holes after repetitive sparks
We do not see this with uRwell, but I do not see why the principle should be different

Explanation tentative presented at RD51 February/09/2022



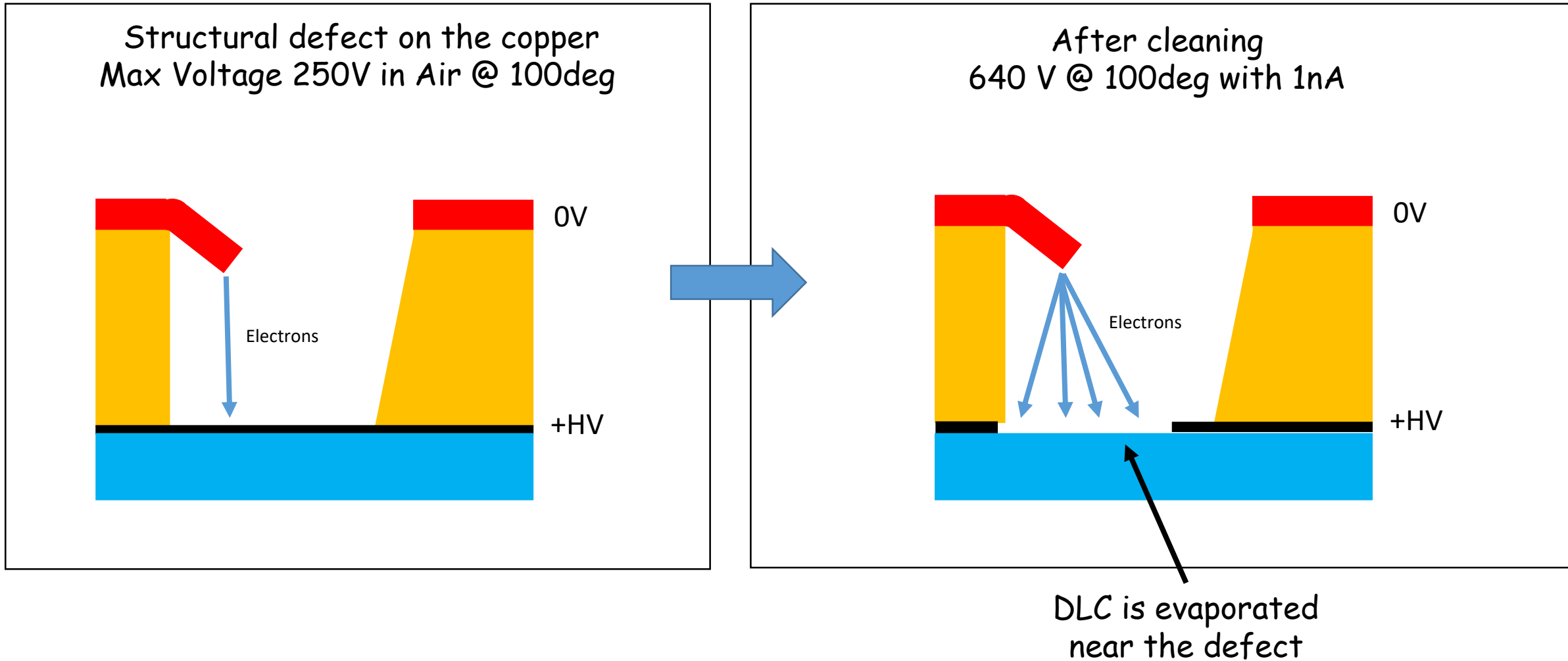
WRONG

Second tentative , first type of defect

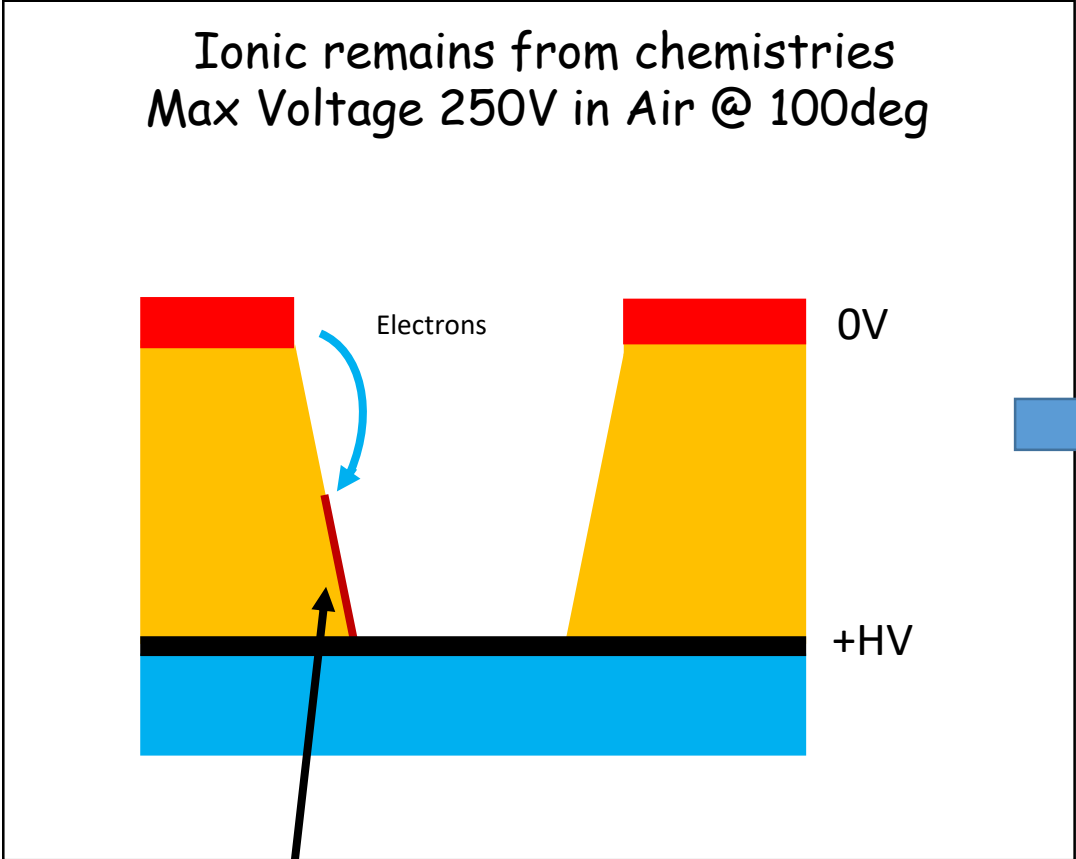


DLC is evaporated
near the defect

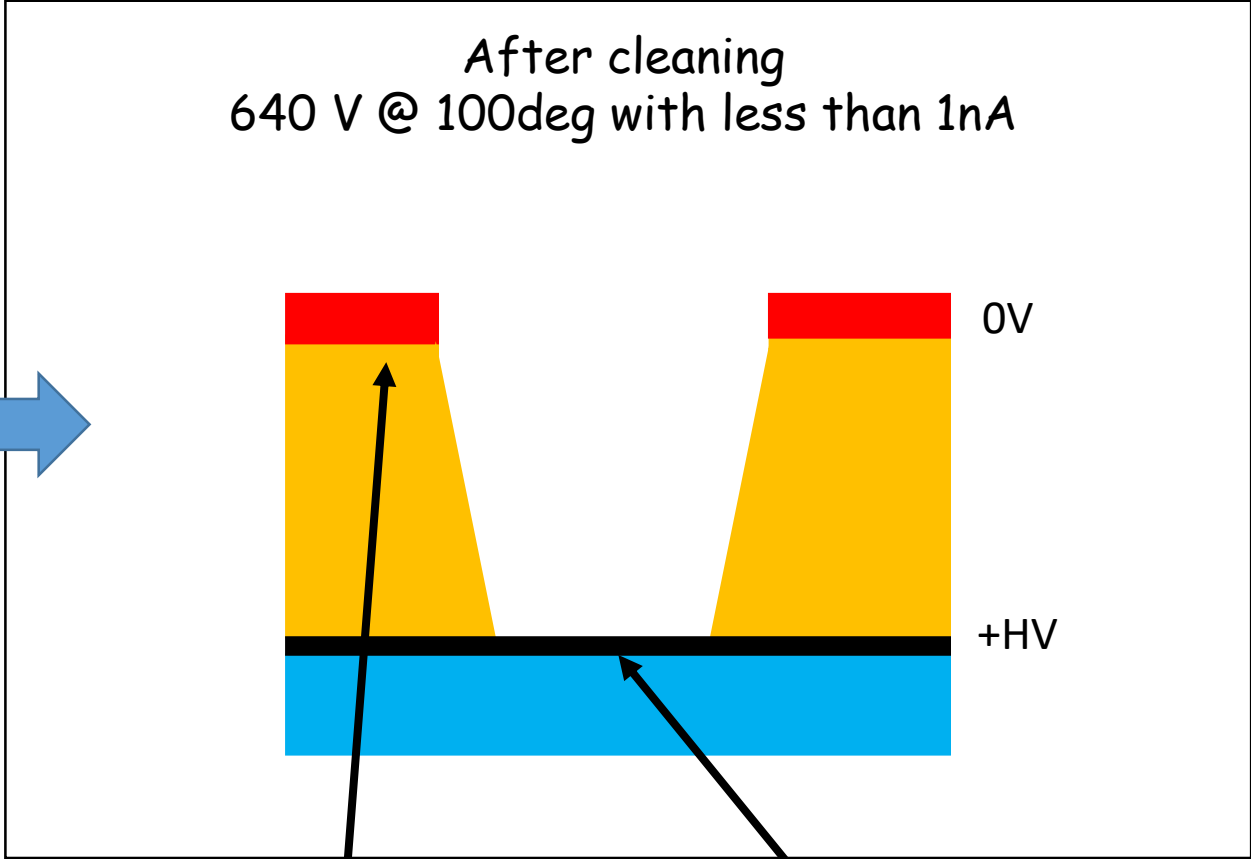
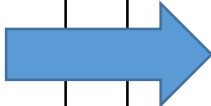
Second tentative , first type of defect



second type of defect (invisible)



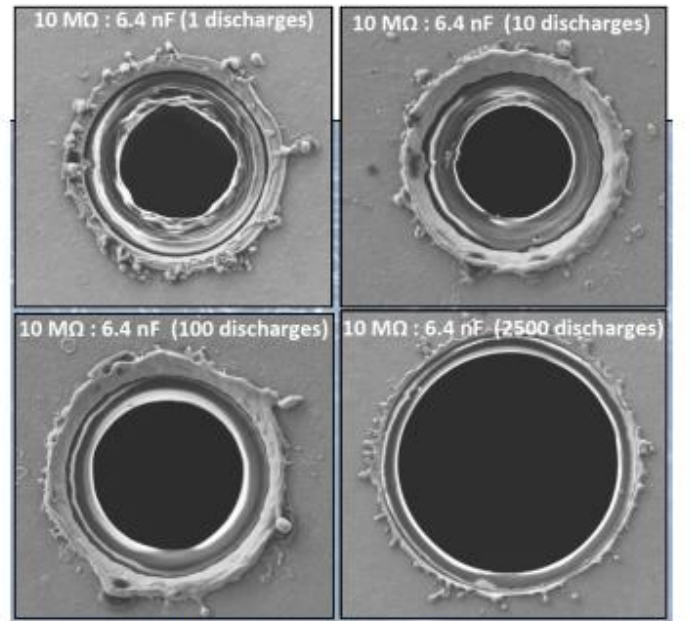
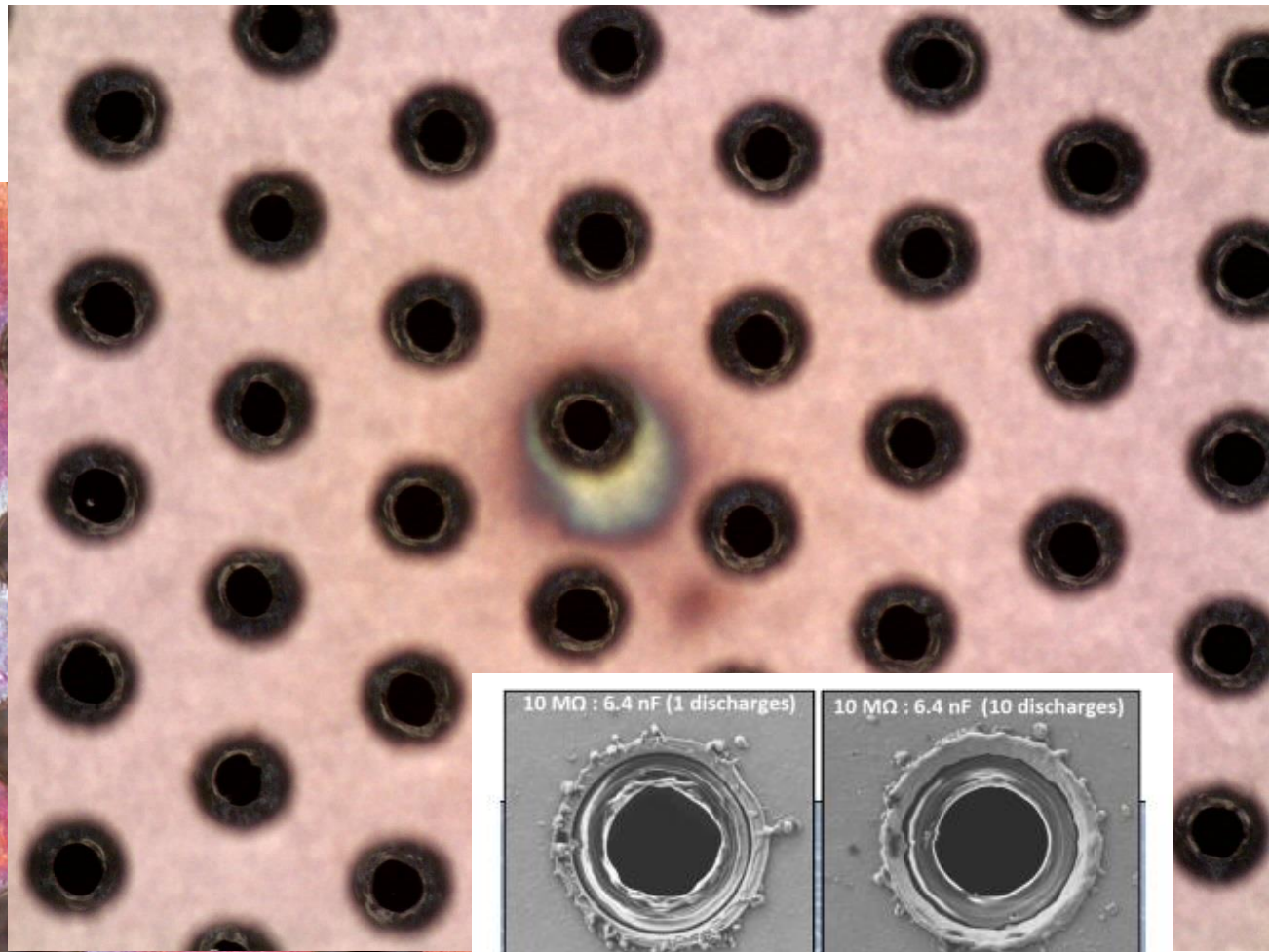
Unknown invisible pollutant



Oxidized copper
→ sign of activity

No DLC ablation
And no more pollutant

After a full week cleaning and billions discharges

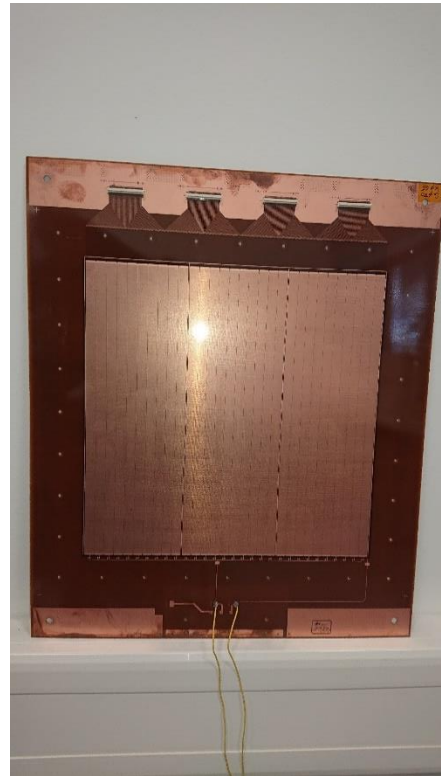


Different than →
the GEM sparking
process

PEP examples



Frascati R&D
1D PEP uRwell
Active area:
40cm x 5cm



Frascati R&D
1D PEP uRwell
Active area:
30cm x 30cm



CLAS12 uRwell
2D PEP with 3 CS layers
Active area:
150cm x 50cm



CLAS12 uRwell
rolled in the oven
for E-cleaning

Whatever is the size, we can always reach a few nA @ 640V/100deg !

New machine

Pulsed DC magnetron reactive PVD

- Max foil size:
-1.7m x 0.6m.

- Resistive layers:
-DLC, semiconductors.
- Photocathodes:
-Metallic, DLC, B4C, GaN, mix?
- Metals:
-AL, Cu, Ni, etc..

- 5 targets.
- 3 simultaneous deposition.
- 3 gas inputs for reactive deposits:
 - H₂, N₂, O₂, C₂H₂, Ar etc..
- 300 deg max built in heater.
- Plasma cleaning



- Fantastic help during from the DLC collaboration Team

- Machine cost (500kCHF) financed by:
 - 25% INFN
 - 25% CERN EP/DT group
 - 50% MPT workshop
- Services cost (150kCHF) financed by:
 - 100% MPT workshop

- Market survey → 04/21
- Invitation to tender → 05/21
- Purchase order → 08/21
- Delivery → 10/22
- Operation → 11/22

- Inner trackers
 - Low mass flexes, Al conductors.
 - Solid state detectors embedded in flex.
- MPGD
 - Resistive protection layers.
 - High rate in difficult background.
 - High granularity low channel count.
 - Ps timing resolution robust cathodes.
 - Layers for neutron detection.
- Other
 - TPC field shapers with continuous distribution.
 - High rate RPCs.

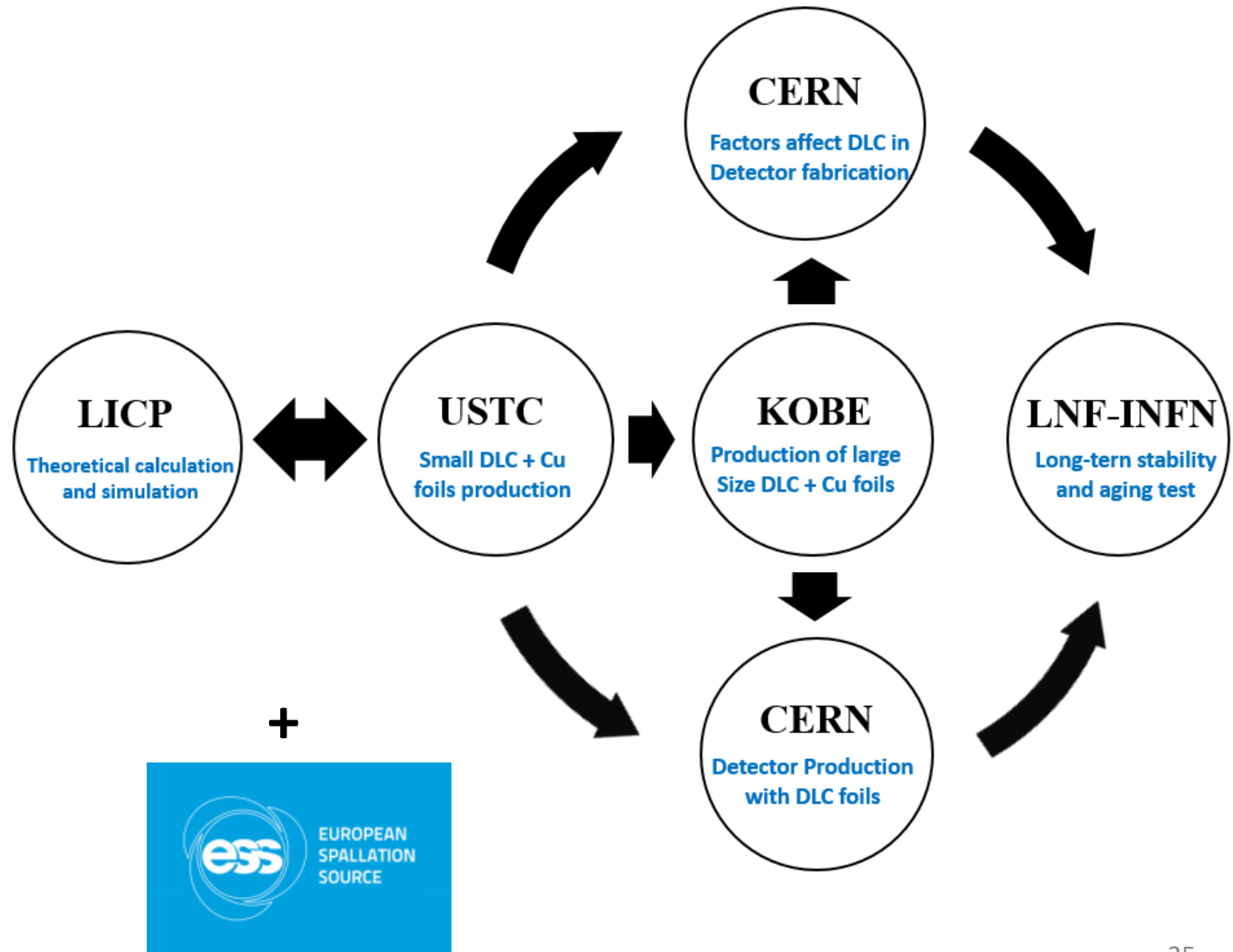
DLC collaboration

Title of project: *DLC based electrodes for future resistive MPGDs*

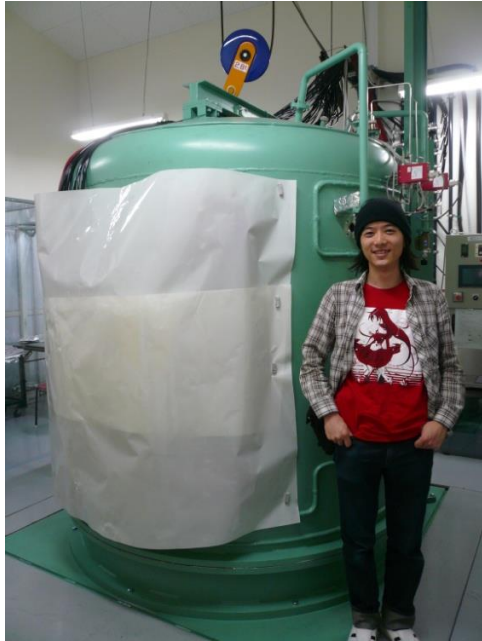
Contact person: *name: Yi Zhou
address: Jinzhai Road No.96, Hefei, Anhui, P.R.China, 230026
telephone number: +86-551-63607940
e-mail: zhouyi@mail.ustc.edu.cn*

- RD51 Institutes:**
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e-mail: zhouyi@mail.ustc.edu.cn*
 2. *Kobe University, contact person: Atsuhiko Ochi
e-mail: ochi@kobe-u.ac.jp*
 3. *CERN
contact person: Rui de Oliveira
e-mail: Rui.de.Oliveira@cern.ch*
 4. *Laboratori Nazionali di Frascati dell'INFN
contact person: Giovanni Bencivenni
e-mail: Giovanni.Bencivenni@lnf.infn.it*

Ext. Collaborators: 1. *State Key Laboratory of Solid Lubrication, Lanzhou Institute of Chemical Physics, Chinese Academy of Sciences, contact person: Lunlin Shang
e-mail: shangll@licp.cas.cn*



Kobe Japan
B-sputter
4 m x 1m real

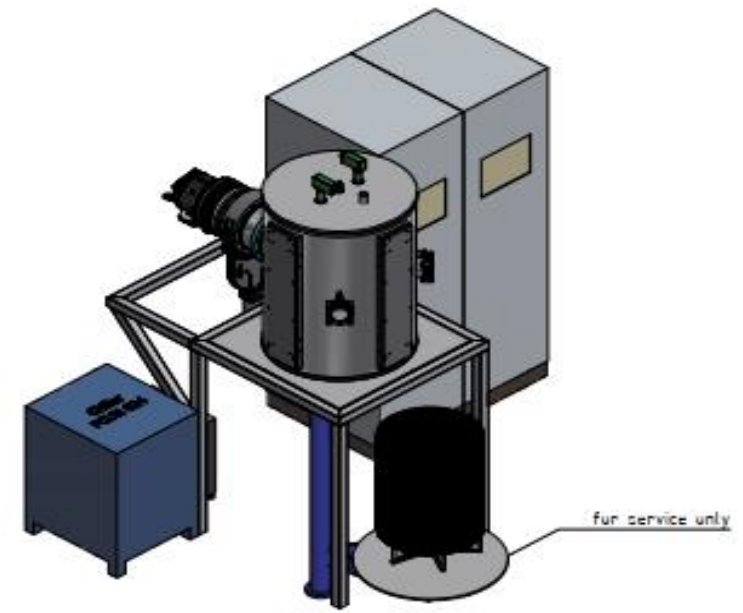
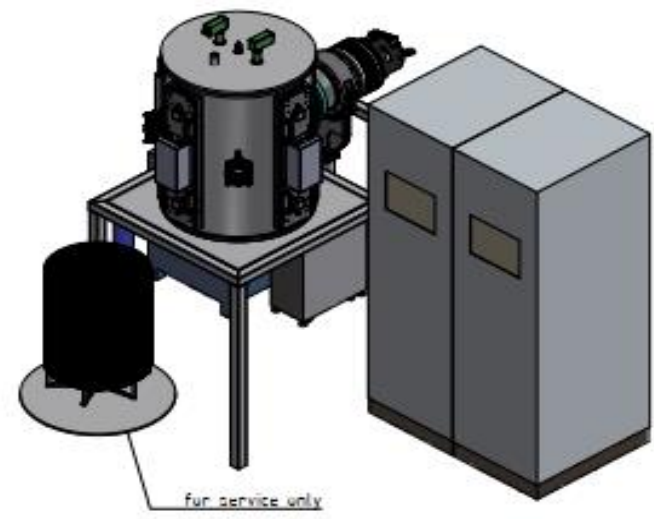
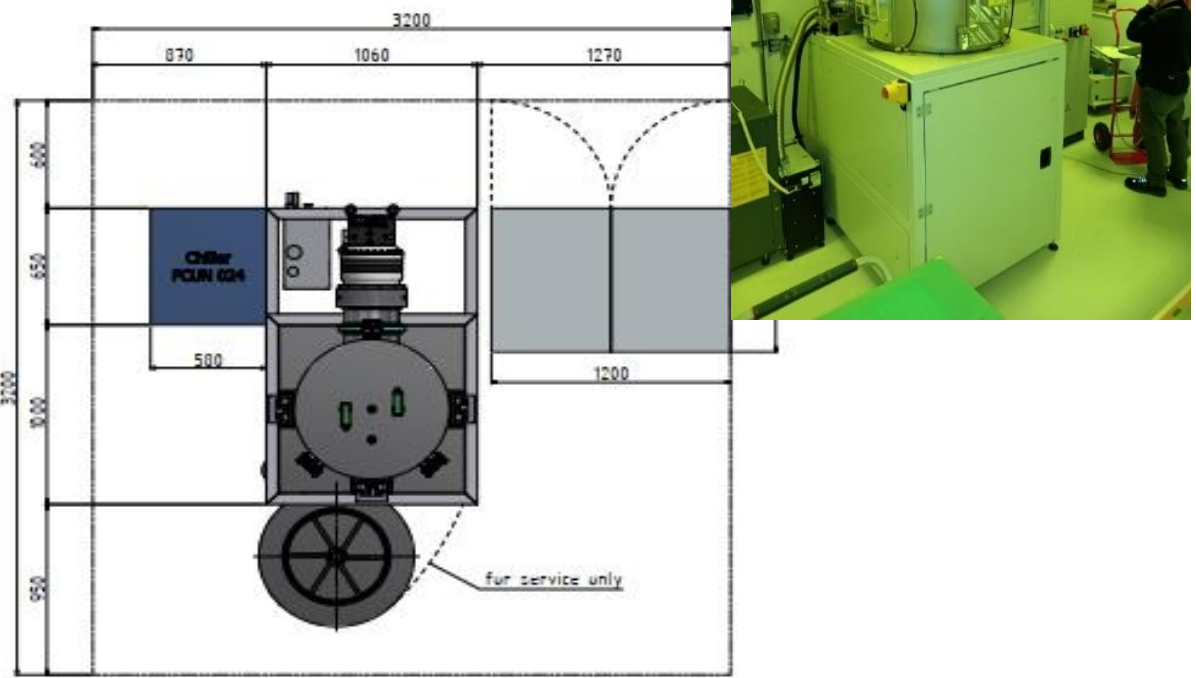
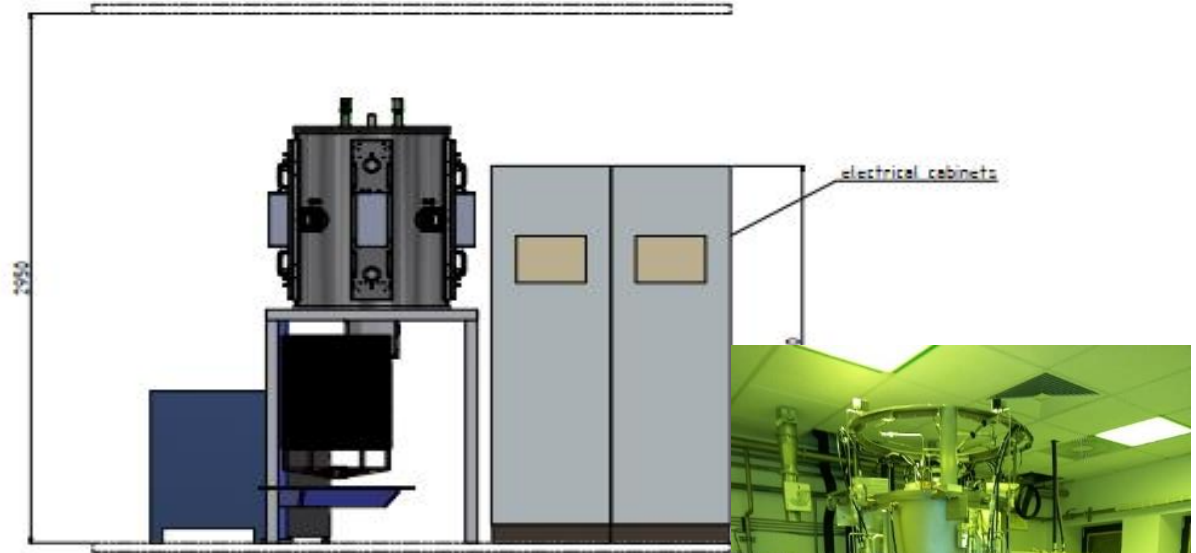


ESS
2.1 m x 400mm



China USTC
1.2 m x 500mm







Drum holding the samples

Possibility to prepare several drums to increase the throughput

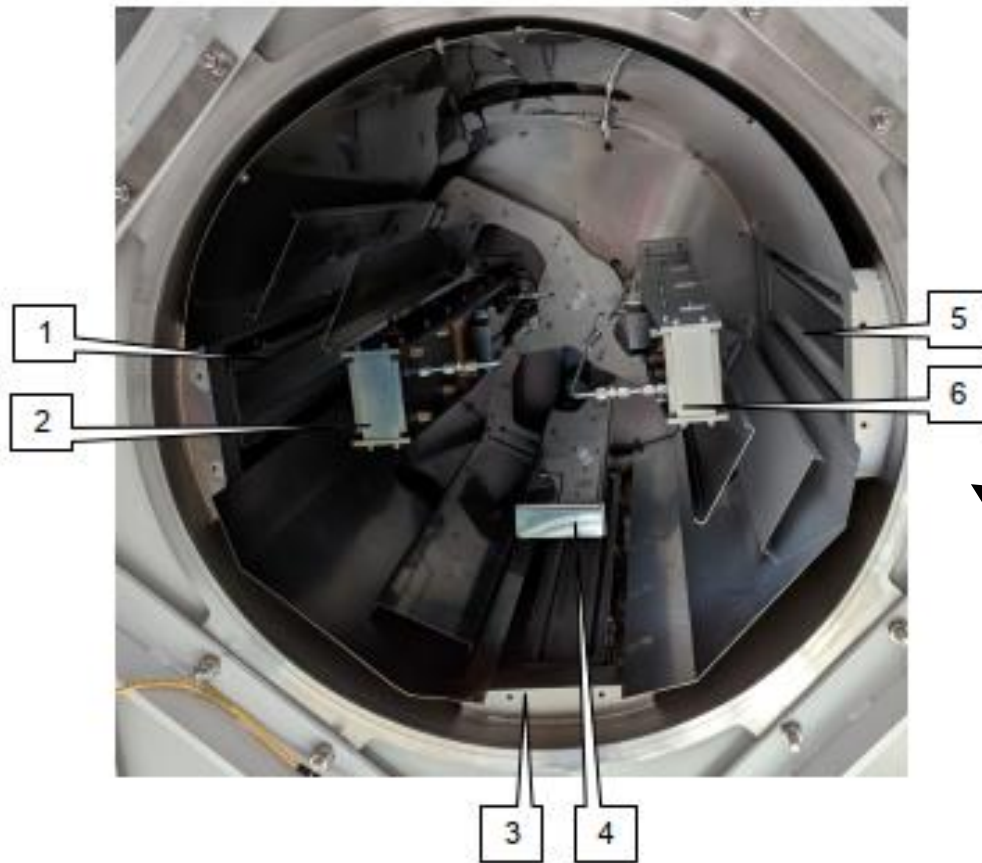


Fig. 6: Recipient – interior



Bottom view of the Vacuum chamber

	<i>Function</i>	<i>Item designation</i>	<i>Remark</i>
1	Cathode 1	+P01-2HT1	Details see circuit diagram
2	Cathode 2	+P01-2HT2	Details see circuit diagram
3	Cathode 3	+P01-2HT3	Details see circuit diagram
4	Heater	+P01-1E1	Details see circuit diagram
5	Cathode 5	+P01-2HT5	Details see vacuum scheme
6	Cathode 4	+P01-2HT4	Details see vacuum scheme

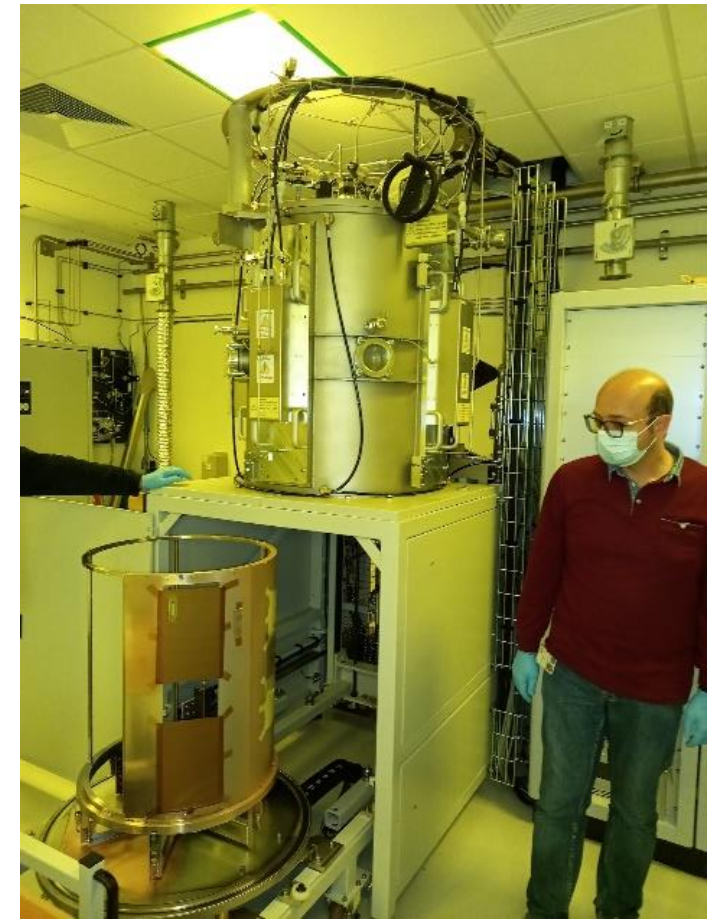
pictures



Machine in operation



70cm copper target installation



Drum unloading
after processing

Preliminary results obtained after few weeks

- Al, Cr and Cu (Ar)
 - Done : excellent results → this was the commissioning test
- DLC (Ar)
 - Done : from 30K to 300K → just playing on the kapton roughness
- DLC-Cr-Cu (Ar)
 - Done : good adhesion, still need a little tuning to be perfect
- DLC (Ar/N₂)
 - Done : from 30K to some Gohms/square
 - Playing on deposit thickness, kapton roughness, N₂ concentration.
- DLC (Ar/C₂H₂), DLC (Ar/CH₄), DLC (Ar/H₂)
 - Not Done
- B₄C, GaN, Si, SiO₂
 - Not Done
- Uniformity test
 - Done : really encouraging → few % over 50cm

The team

- Serge Ferry (MPT)
 - Expert in the field
 - He co-designed the machine
 - He wrote all the specifications
 - He is now leading the preliminary test program
- Givi
 - He participated to the commissioning
 - Participation to preliminary test program
- Gianfranco Morello (Frascati)
 - He participated to the commissioning
 - Participation to preliminary test program

Better quantitative results will be given at the next RD51

Next

- PEP uRwell:
 - Produce 2 more 1.5m x 0.5m PEP uRwell
 - Fully automatize the electrical cleaning to reduce the uRwell cost.
 - Continue the uRwell technology transfer to industry
- Vacuum machine:
 - Improve our knowledge on N₂ doped high resistive value DLC layers
 - Start some test with C₂H₂
 - B₄C ?
 - We are ready to accept requests from the community for DLC layers.
- In next RD51 meeting I will give news on :
 - High rate SBU MM
 - High rate SBU uRwell
 - Capacitive sharing